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PPLICATION NO.		FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO	
10/609,236		06/26/2003	Venkat Selvamanickam	SPP 18.809 7733		
26304	7590	10/28/2005		EXAMINER		
		N ROSENMAN LL	KACKAR, RAM N			
575 MADIS				ART UNIT	PAPER NUMBER	
	•			1763		
			DATE MAILED: 10/28/2005			

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)						
Office Action Cum		10/609,236	SELVAMANICKAN	VI ET AL.					
Office Action Sumi	nary	Examiner	Art Unit						
		Ram N. Kackar	1763						
The MAILING DATE of this Period for Reply	communication appe	ears on the cover sheet with the c	orrespondence ad	dress					
 Failure to reply within the set or extended pe 	M THE MAILING DA re provisions of 37 CFR 1.13 of this communication. maximum statutory period wi riod for reply will, by statute, ree months after the mailing	TE OF THIS COMMUNICATION	N. nely filed the mailing date of this co D (35 U.S.C. § 133),						
Status									
1) Responsive to communicat	ion(s) filed on 17 Au	iaust 2005.							
2a)⊠ This action is FINAL.		action is non-final.	•						
3) Since this application is in a									
	closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.								
Disposition of Claims									
4)	is/are withdrawed. 1 is/are rejected. 1 ted to.	n from consideration.							
Application Papers									
9) The specification is objected to by the Examiner.									
10)☐ The drawing(s) filed on is/are: a)☐ accepted or b)☐ objected to by the Examiner.									
	Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).								
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).									
11)☐ The oath or declaration is ol	1) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.								
Priority under 35 U.S.C. § 119									
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 									
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Attachment(s)									
 Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing 	Review (PTO-948)	4) 🔲 Interview Summary Paper No(s)/Mail Da	(PTO-413) ite						
Information Disclosure Statement(s) (PT Paper No(s)/Mail Date 8/79/2005.	O-1449 or PTO/SB/08)		atent Application (PTO	-152)					

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DETAILED ACTION

Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 1-4, 7-11 and 25-31 are rejected under 35 U.S.C. 103(a) as being unpatentable over Lijima et al (2001/0006042) in view of Vaidya et al (US 5076203).

Lijima et al disclose a process for cooling and positioning a translating substrate (tape like) which could be comprise metal like nickel (Paragraph 59) in a deposition chamber for vacuum deposition (abstract and Fig 3), gas inlet (38), source of deposition material (36), means of delivering the deposition material (ion beam -38), means of translating a substrate (24,25), means of positioning the substrate so that deposition material impinges on the substrate (23) whereas the substrate positioning means contains internal gaseous coolant delivery channels through nozzles (Fig 5-60) which could comprise nitrogen or oxygen as a part of air (paragraph 65 and 86). Lijma et al further teach that the process is used for making a buffer layer of yttrium stabilized zirconia (YSZ) or MgO for a superconducting film (Abstract and paragraph 71) using ion assist (39).

Further Lijma et al teach that FWHM (full width at half maximum) is the measure of biaxial texture (indicator of crystal orientation- Paragraph 99) and that it could be

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minimum at an incidence angle of 50-60 degrees (paragraph 16,87 and 99). Further Lijma et al disclose various parameters affecting FWHM and disclose it to be below 10 degrees (Fig 13).

Lijma et al teach that substrate positioning means contains internal gaseous coolant delivery channels but fail to disclose additional liquid coolant channels and specific size of gas orifices.

Vaidya et disclose a process for cooling and positioning a translating substrate in a deposition chamber for vacuum deposition (Col 1 lines 8-11), gas inlet (Fig 1-17, Fig 6-30), source of deposition material (Fig 6-27), means of delivering the deposition material (electron –beam heater (Col 3 line 35), means of translating a substrate (Fig 6-22) from 0-90 meters per min (Abstract), curved means of positioning the substrate so that deposition material impinges on the substrate (23) whereas the substrate positioning means contains internal liquid coolant channels (23a and 23b) and internal gaseous coolant delivery channels (Fig 6-30, Fig 7-10 and Col 6 lines 5-68) which could use oxygen or argon to allow the temperature from 0 degrees C upwards.

As discussed above Vaidya et al disclose the substrate positioning means contains internal liquid coolant channels (23a and 23b) and internal gaseous coolant delivery channels in three different ways. First being from the side through injecting through holes (as in Fig 6-30 and Fig 2-16a) and the other two being from behind the support either through porous fixed support (Fig 7-10 and Col 6 lines 5-20) or through an enclosed cavity (Fig 7-10 and Col 6 lines 44-68).

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Furthermore Vaidya et al teach that these features could be combined (Col 6 lines 44-68) and teach that the injection holes could be 1.5 mm diameter at 15 mm pitch (Col 4 lines 3-9).

Therefore having liquid coolant channels would have been obvious for one of ordinary skill in the art at the time of invention since liquid coolant channels help to remove the heat from the positioning means.

Since the hole diameter and spacing determine the amount of gas and its distribution behind the substrate which affects amount and uniformity of cooling it would have been obvious for one of ordinary skill in the art at the time of invention to replace the porous outlets in the support by spaced holes to distribute sufficient gas behind the tape substrate for optimum heat transfer and reduced friction.

3. Claim 5 is rejected under 35 U.S.C. 103(a) as being unpatentable over Lijima et al (2001/0006042) in view of Vaidya et al (US 5076203) as applied to claims 1-4, 7-11 and 25-31 and further in view of Cavalca et al (20010033960).

Lijima et al in view of Vaidya et al is discussed above.

Lijima et al in view of Vaidya et al disclose a deposition chamber for vacuum deposition and means of delivering the deposition material as (electron-beam heater Col 3 line 35) but fail to disclose other means of delivery conventionally used for physical vapor deposition on tape substrates like magnetron sputtering.

Cavalca et al disclose vacuum deposition methods and teach that physical vapor deposition, ion beam sputtering and magnetron sputtering are for good control of

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uniformity, thickness and contamination free deposition of large surfaces in a reel to reel web type of substrates where coating on large surfaces is required (Paragraph 156).

Therefore it would have been obvious for one of ordinary skill in the art at the time of invention to use magnetron sputtering as an alternative means of delivery since this technique is typical and conventional for coating on large surfaces with advantage.

Response to Arguments

Applicant's arguments filed 8/17/2005 have been fully considered but they are not persuasive.

The arguments relate to the deficiency of Vaidya et al in disclosing the new limitation of an IBAD apparatus added in the last amendment. These arguments are now moot in view of new grounds of rejection presented in this office action.

Conclusion

Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any

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extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the

advisory action. In no event, however, will the statutory period for reply expire later than

SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Ram N. Kackar whose telephone number is 571 272 1436.

The examiner can normally be reached on M-F 8:00 A.M to 5:P.M.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Parviz Hassanzadeh can be reached on 571 272 1435. The fax phone number

for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the

Patent Application Information Retrieval (PAIR) system. Status information for

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have questions on access to the Private PAIR system, contact the Electronic Business

Center (EBC) at 866-217-9197 (toll-free).

Ram Kackar

Examiner AU 1763